

Notice of References Cited		Application No. 09/510,375	Applicant(s) Williams S	
		Examiner H. Kim	Group Art Unit 2185	Page 1 of 1

U.S. PATENT DOCUMENTS					
*	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A	5,893,136	4/1999	Stolt et al,	711	105
B	5,721,860	2/1998	Stolt et al,	711	105
C	5,630,163	5/1997	Fung et al,	710	127
D	5,604,880	2/1997	Dipert	711	103
E	5,568,651	10/1996	Medina et al,	710	74
F	5,325,513	6/1991	Tanaka et al,	710	16
G	5,307,320	4/1994	Farrer et al,	365	230.01
H	5,278,801	1/1994	Dresser et al,	365	230.02
I	5,261,064	11/1993	Wyland	711	211
J	5,253,357	10/1993	Allen et al,	711	115
K					
L					
M					

FOREIGN PATENT DOCUMENTS						
*	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
N						
O						
P						
Q						
R						
S						
T						

NON-PATENT DOCUMENTS	
*	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)
U	Micron, "Reduce DRAM cycle times with Extended Data-Out", Technical note, 1994 DATA DRAM DATA BOOK, MICRON Semiconductor, Inc. PP 5-33 thru 5-40
V	Old SIMCHECK Product Line, [Online] Available http://www.simcheck.com/Sim1pl.htm
W	Kristina Sullivan, "Simcheck add-on lets users identify faulty DRAM chips", PC Week, VT n18 p18(CD).
X	

* A copy of this reference is not being furnished with this Office action.
(See Manual of Patent Examining Procedure, Section 707.05(a).)